

Evaluation of Thin-Film Photodevices and Development of Artificial Retina

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Abstract

First, thin-film photodevices are evaluated, and a p/i/n thin-film phototransistor (TFPT) is recommended because the photo-induced current is relatively high and independent of the applied voltage. Next, an artificial retina is developed using the p/i/n TFPTs, and it is found that it can detect photo illuminance profile with sensitivity control.

1. Introduction

Thin-film photodevices are promising for photosensor applications such as ambient light sensors¹, image scanners², artificial retinas³⁻⁵, etc. In these applications, since the thin-film photodevices are integrated with low-temperature poly-Si thin-film transistors (LTPS-TFTs), advanced functions can be acquired. Moreover, since the thin-film photodevices are fabricated using the same fabrication processes as

LTPS-TFTs, fabrication costs can be saved. However, the thin-film photodevices have not sufficiently been evaluated and presented from the viewpoints of the device structures and driving conditions. In our research, first, a p/i/n thin-film photodiode (TFPD), p/n TFPD and p/i/n thin-film phototransistor (TFPT) are evaluated, and the p/i/n TFPT is recommended because the photo-induced current (I_{photo}) is proportional to the photo illuminance (L_{photo}), relatively high and independent of the applied voltage (V_{apply}).

On the other hand, artificial retinas are promising because they may recover light for the blind⁶ and provide new applications of information electronics⁷. Until now, bulk Si metal-oxide-semiconductor field-effect transistors (MOSFETs) have commonly been used for artificial retinas. In our research, next, an artificial retina is developed using the p/i/n TFPTs and LTPS-TFTs, and it is found that it can detect the L_{photo} profile and correspondingly output the output

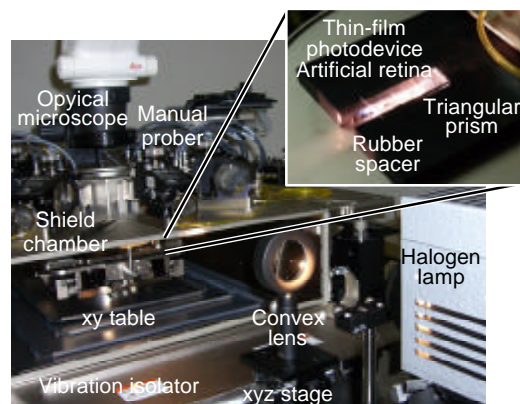
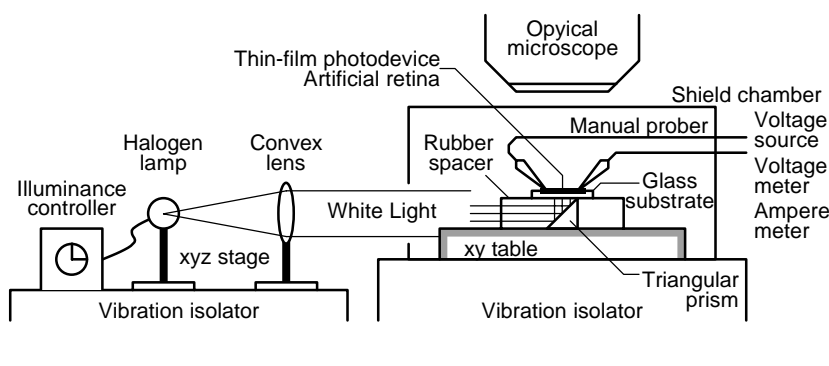


Fig. 1. Measurement system.

voltage (V_{out}) profile with sensitivity control. This artificial retina is expected to be suitable for living bodies because it can potentially be fabricated on the plastic substrate⁸.

2. Experiment

The thin-film photodevices and artificial retina are fabricated on the glass substrate using the same fabrication processes as conventional LTPS-TFTs. First, the amorphous-Si film is deposited using low-pressure chemical-vapor deposition (LPCVD) of Si_2H_6 and crystallized using XeCl excimer laser to form the poly-Si film. Next, SiO_2 film is deposited using plasma-enhanced chemical-vapor deposition (PECVD) of tetraethylorthosilicate (TEOS) for the gate-insulator film. The gate-metal film is deposited and patterned. The phosphorous and boron are implanted and thermally activated for the anode-cathode regions of the thin-film photodevices and source-drain regions of the LTPS-TFTs. The hydrogen

plasma treatment, oxygen plasma treatment and water-vapor heat treatment are performed to improve the poly-Si film, SiO_2 film and their interfaces.

The measurement system is shown in Fig. 1. The thin-film photodevices and artificial retina are located on a rubber spacer in a shield chamber and connected via a manual prober to a voltage source, voltage meter and ampere meter. White light from a halogen lamp is formed to be parallel through a convex lens, reflected by a triangular prism and irradiated through the glass substrates to the back surfaces of the thin-film photodevices and artificial retina. The I_{photo} is measured with changing the L_{photo} and V_{apply} in the case of the thin-film photodiode. The V_{out} profile is measured with giving the L_{photo} profile in the case of the artificial retina.

3. Thin-film photodevices

Thin-film photodevices generate the I_{photo} caused by the generation mechanism of electron-hole pairs at

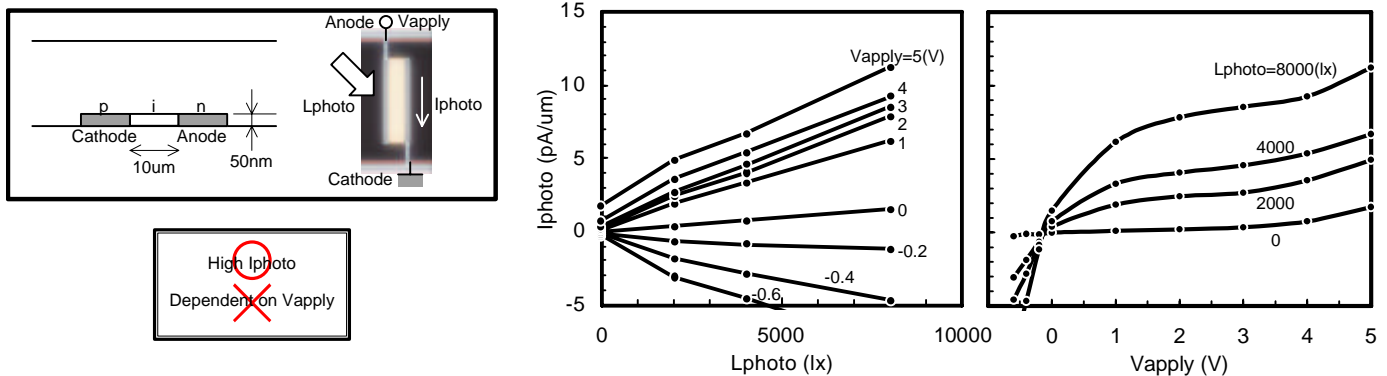


Fig. 2. p/i/n thin-film photodiode.

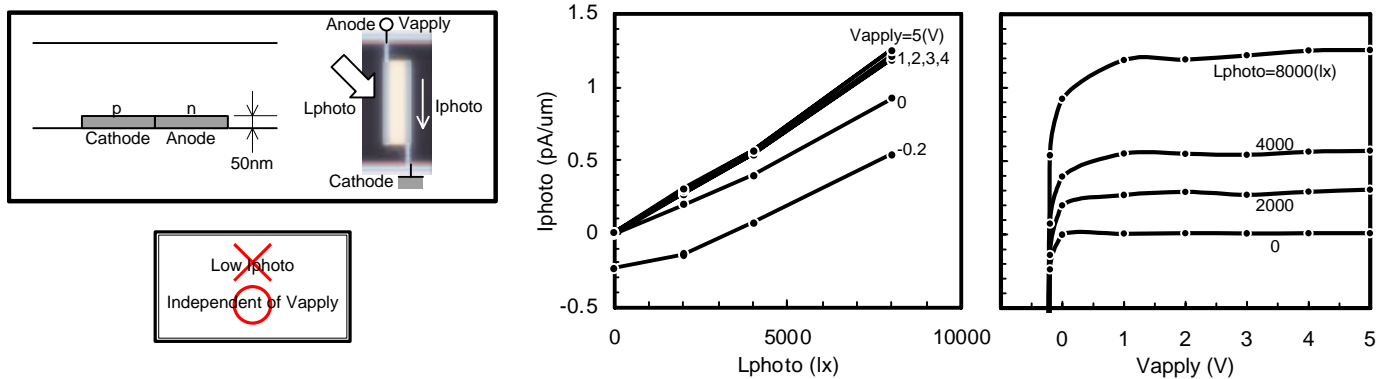


Fig. 3. p/n thin-film photodiode.

semiconductor regions where the L_{photo} is irradiated, the depletion layer is formed and the electric field is applied. Since thin-film photodevices are mostly used to detect the L_{photo} and the V_{apply} often unintentionally changes in the circuit configuration, it is preferable that the I_{photo} is dependent only on the L_{photo} but independent of the V_{apply} .

First, the characteristic of the p/i/n TFPT is shown in Fig. 2. It is found that the I_{photo} is proportional to the L_{photo} and relatively high but dependent on the V_{apply} . This is because: The depletion layer is formed in the whole intrinsic region, which means that the generation volume of electron-hole pairs is large, and the I_{photo} is relatively high. However, the electric field increases as the V_{apply} increases, which means that the generation rate increases, and the I_{photo} is dependent on the V_{apply} .

Next, the characteristic of the p/n TFPT is shown in Fig. 3. It is found that the I_{photo} is not high but independent of the V_{apply} . This is because: The depletion layer is formed only near the p/n junction due to a built-in potential, which means that the generation volume of electron-hole pairs is small, and the I_{photo} is not high. However, the electric field is always high, which means the generation rate is constant, and the I_{photo} is independent of the V_{apply} .

Finally, the characteristic of the p/i/n TFPT is shown in Fig. 4, where the gate voltage (V_{gate}) is optimized. It is found that the I_{photo} is simultaneously relatively high and independent of the V_{apply} . This is because: The depletion layer is formed in the whole intrinsic region, which means that the generation volume of electron-hole pairs is large, and the I_{photo} is relatively high. Moreover, the electric field is always high because it is mainly determined by the V_{gate} , which means that the generation rate is

constant, and the I_{photo} is independent of the V_{apply} . Therefore, the the p/i/n TFPT is recommended.

4. Artificial retina

First, the characteristic of the retina pixel is shown in Fig. 5. The retina pixel consists of the p/i/n TFPT, a current mirror and load transistors. It is found that the output voltage (V_{out}) increases as the L_{photo} increases, and its sensitivity can be controlled by the bias voltage (V_{bias}).

Next, the characteristic of the retina array is also shown in Fig. 5. It is found that this artificial retina can detect the L_{photo} profile and correspondingly output the output voltage (V_{out}) profile. Although some noises occur due to the characteristic deviations of the p/i/n TFPTs and LTPS-TFTs, the shape of the V_{out} profile is roughly the same as the shape of the L_{photo} profile.

5. Conclusion

First, thin-film photodevices were evaluated, and a p/i/n TFPT was recommended because the I_{photo} is relatively high and independent of the V_{apply} . Next, an artificial retina was developed using the p/i/n TFPTs, and it was found that it can detect the L_{photo} profile with sensitivity control. This artificial retina is expected to be suitable for living bodies because it can potentially be fabricated on the plastic substrate.

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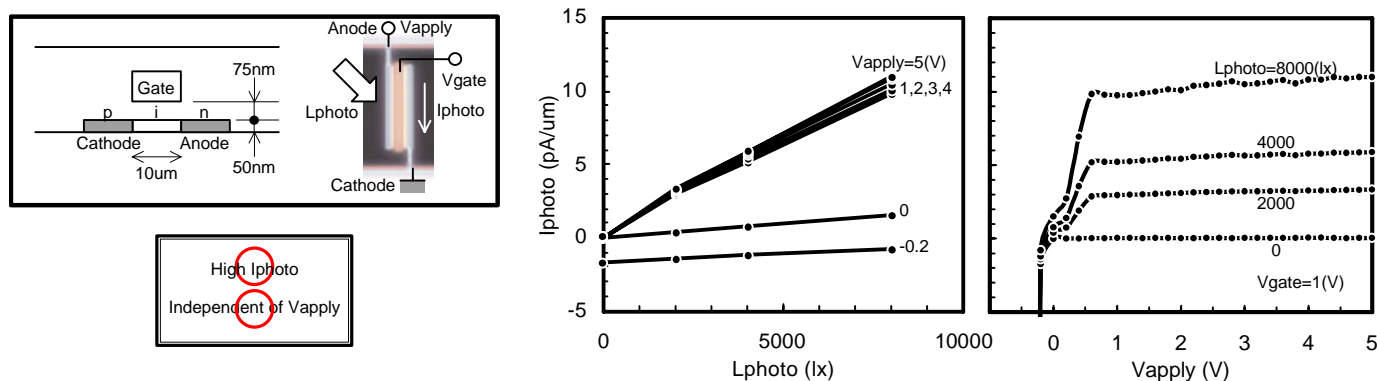


Fig. 4. p/i/n thin-film phototransistor.

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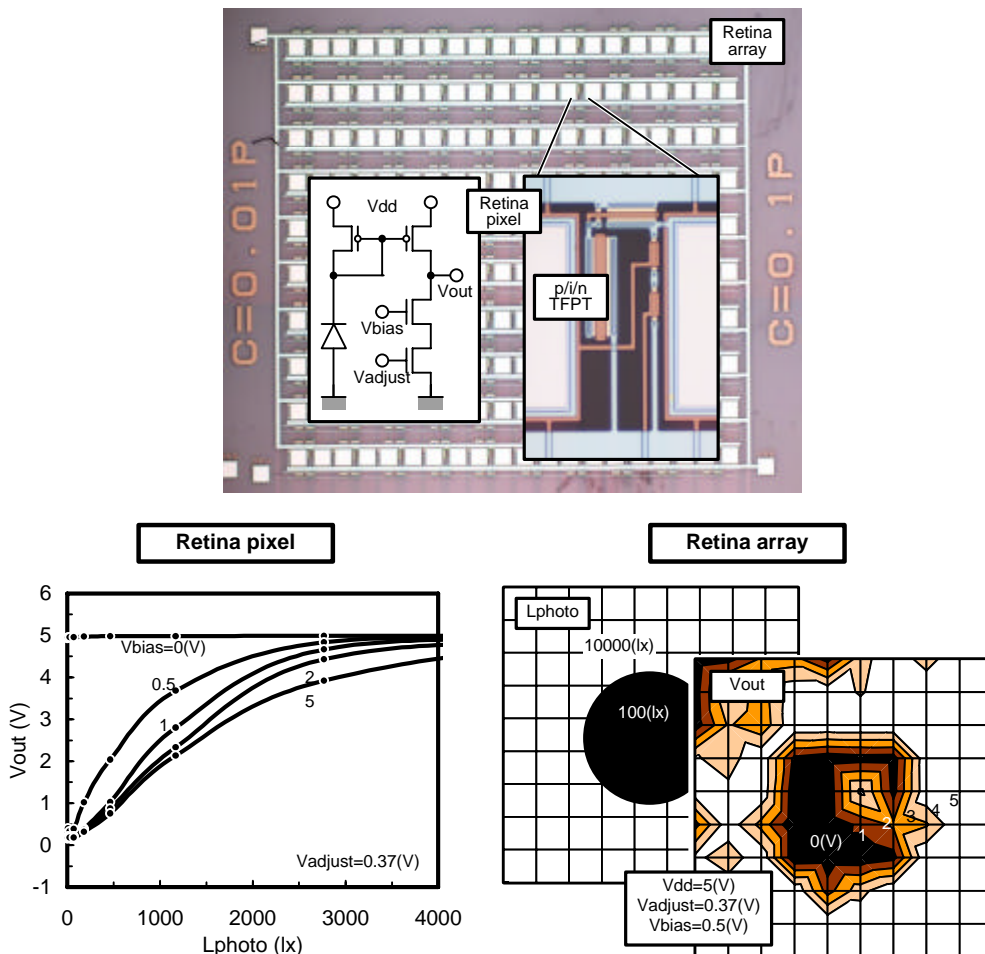


Fig. 5. Artificial retina.